PATENT

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ABSTRACT OF THE DISCLOSURE

The invention relates to an integrated test circuit in an integrated circuit for testing a plurality of internal voltages. A switching device is provided to select one of the internal voltages in accordance with a selection signal for the purpose of testing, and a comparator device is provided in order to compare a measurement voltage, dependent on the selected internal voltage, with an externally provided reference voltage. An error signal is output as a result of the comparison.

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